Notice of References Cited

Application/Control No. 10/784,715	Reexamination	Applicant(s)/Patent Under Reexamination KIM, KWANG-CHUL		
Examiner	Art Unit			
YOUNG T. TSE	2611	Page 1 of 1		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
*	Α	US-6,021,165 A	02-2000	Ohkubo et al.	375/344	
*	В	US-6,148,045 A	11-2000	Taura et al.	375/344	
*	С	US-6,373,861 B1	04-2002	Lee, Hyun-Kyu 370		
*	D	US-6,647,066 B1	11-2003	Szajnowski, Wieslaw Jerzy	375/260	
*	E	US-2004/0120410 A1	06-2004	Priotti, Paolo	375/260	
*	F	US-2005/0169408 A1	08-2005	Kim, Kwang-chul	375/343	
*	G	US-6,993,083 B1	01-2006	Shirakata et al.	375/260	
*	Η	US-2007/0036231 A1	02-2007	ldo, Jun	375/260	
	_	US-				
	J	US-				
	K	US-	7.1			
	اد ا ا	US-				
	М	US-				

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	1 195 961 A2	10-2002	EP	Seo et al.	
	0					
	Р			_	,	
	α					
	R					
	S					
	Т	•				

NON-PATENT DOCUMENTS

*						
<u> </u>	<u> </u>	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	w					
	×					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.